Docket No.: 50090-265

UTILITY PATENT APPLICATION UNDER 37 CFR 1.53(b)

Box PATENT APPLICATION
Commissioner for Patents
Washington, DC 20231
Sir:



Transmitted herewith for filing is the patent application of:

INVENTOR: Kiyotoshi UEDA, Shoichi OOSHITA

FOR: METHOD AND APPARATUS FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUIT, AND SEMICONDUCTOR INTEGRATED CIRCUIT

MANUFACTURED THEREBY

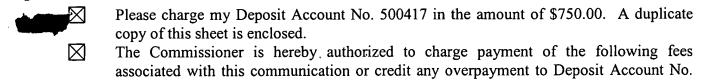
Enclose	ed are:					
\boxtimes	20 pages of specification, claims, abstract.					
\boxtimes	Declaration and Power of Attorney.					
\boxtimes	Priority Claimed.					
	Certified copy of Japanese Patent Application 2000-216321					
\boxtimes	7 sheets of formal drawing.					
\boxtimes	An assignment of the invention to Mitsubishi Denki Kabushiki Kaisha					
	and the assignment recordation fee.					
	An associate power of attorney.					
	A verified statement to establish small entity status under 37 CFR 1.9 and 37 CFR 1.27.					
	Information Disclosure Statement, Form PTO-1449 and reference.					
\boxtimes	Return Receipt Postcard					

The filing fee has been calculated as shown below:

	NO. OF		EXTRA		
*	CLAIMS		CLAIMS	RATE	AMOUNT
Total Claims	14	-20	0	\$18.00	\$0.00
Independent Claims	2	-3	0	\$80.00	\$0.00
	\$0.00				
	\$710.00				
	\$710.00				
	\$0.00				
	\$40.00				
	\$7 \$ 0.00				



PATENT TRADEMARK OFFICE



500417. A duplicate copy is enclosed.

Any additional filing fees required under 37 CFR 1.16.

The Commissioner is hereby authorized to charge payment of the following fees during the pendency of this application or credit any overpayment to Deposit Account No. 500417. A duplicate copy of this sheet is enclosed.

Any patent application processing fees under 37 CFR 1.17.

Any filing fees under 37 CFR 1.16 for presentation of extra claims.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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